nunano

A Nu approach to AFM Probes

www.nunano.com

+44 117 299 3093 | info@nunano.com

Cut me out and put me on your lab door!

NuNano

A Nu approach to AFM Probes

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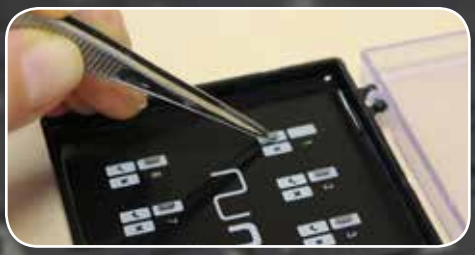
- **Guaranteed tip sharpness with every probe inspected**
- **Minimal variation between probes with unrivalled control of cantilever dimensions**
- **Organise your probes with our Unique Gel-Pak® layout**



"I found NuNano probes to be reliable and robust. They produced great images and the customer service was exceptionally good."

- Prof. Jamie Hobbs, University of Sheffield (2020)

Quality

Our proprietary manufacturing processes result in AFM probes with the best dimensional tolerances available.

Price

Our combination of high quality products and exemplary customer service is brought to you with no increase in prices.

Service

We strive to offer the best experience for AFM users. From choosing your probes to storing your probes, we're with you all the way.

Experience

Founded from a world-renowned research group in Bristol, NuNano builds on over 30 years of AFM expertise.

Contact us today to discuss your probe requirements

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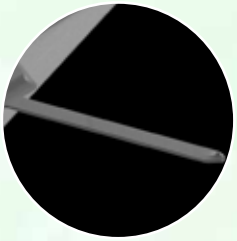
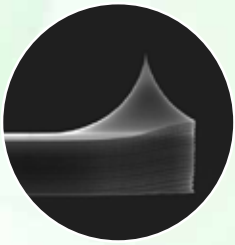
SCOUT

Our silicon AFM probes

General purpose AC mode silicon AFM probes exhibiting exemplary dimensional tolerances and tip sharpness. Applications include non-contact and soft tapping modes in air, and force modulation.



SCOUT 70
2 N/m : 70 kHz



SCOUT 150
18 N/m : 150 kHz

SCOUT 350
42 N/m : 350 kHz

Nominal cantilever parameters:

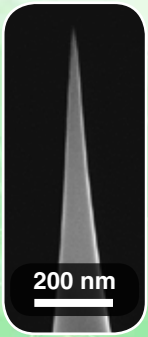
- Rectangular cross-section with ± 0.5 µm thickness
- Length & width controlled to ±1.5 µm
- Free end shaped to define tip position

Nominal tip parameters:

- Conical profile with 25° cone angle at apex
- 5 nm tip radius (guaranteed < 10 nm)
- Accurately defined tip position

Upgrade to a High Aspect Ratio (HAR) tip

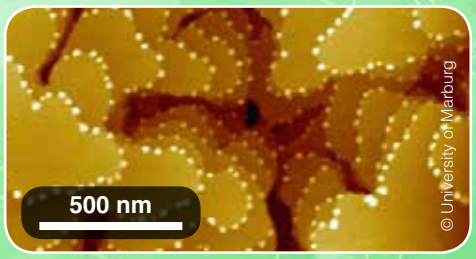
- Ideal for deep-trench imaging and highly three-dimensional samples
- Conical profile with < 15° cone angle over the last 1 µm of the tip



Choose your reflective coating

- Prevent laser interference and increase the intensity of the reflected laser signal by using a reflective coating
- Choose either an aluminium or gold reflective coating or request an uncoated probe

ALUMINIUM | GOLD | UNCOATED



C60 nanoclusters on pentacene step edge
with **SCOUT 350 RAI**

Heptacene-based crystallites on Al_2O_3
with **SCOUT 350**

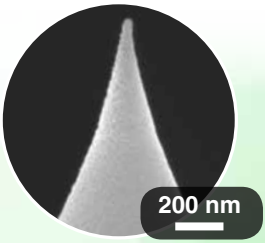
SPARK

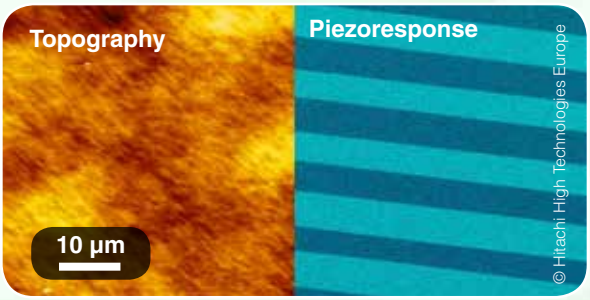
Our conductive AFM probes

Conductive platinum coated AFM probes for electrical AFM measurements in AC and contact modes.

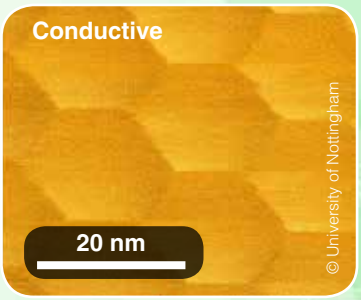
- 40 nm platinum coating with 5 nm titanium adhesion layer on both sides of the probe
- 18 nm tip radius (guaranteed < 30 nm)

Available with the same mechanical specifications as our SCOUT probes.





Periodically poled lithium niobate surface with SPARK 70 Pt



Strained MBE graphene on hBN flakes with SPARK 70 Pt

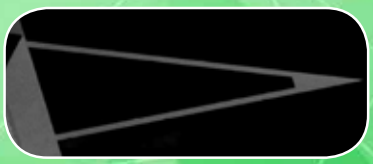
QUEST

Our tip-less silicon nitride probes

New Release

For force spectroscopy and other applications requiring high force sensitivity.

- Triangular and rectangular cantilevers
- Spring constant range 0.005 to 0.5 N/m



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